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|-----------------------------------|--|-------------------------|--|-------------|
| <b>Notice of References Cited</b> |  | Application/Control No. | Applicant(s)/Patent Under Reexamination<br>SHAH ET AL. |             |
|                                   |  | Examiner<br>Thien M. Le | Art Unit<br>2876                                       | Page 1 of 1 |

**U.S. PATENT DOCUMENTS**

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Name                | Classification |
|---|---|--|-----------------|---------------------|----------------|
| * | A | US-6,836,773                                     | 12-2004         | Tamayo et al.       | 707/6          |
| * | B | US-6,694,307                                     | 02-2004         | Julien, Benoit      | 707/3          |
| * | C | US-6,671,818                                     | 12-2003         | Mikurak, Michael G. | 714/4          |
| * | D | US-6,253,238                                     | 06-2001         | Lauder et al.       | 709/217        |
| * | E | US-6,101,537                                     | 08-2000         | Edelstein et al.    | 709/219        |
| * | F | US-2004/0260781                                  | 12-2004         | Shostack et al.     | 709/207        |
| * | G | US-2004/0249811                                  | 12-2004         | Shostack et al.     | 707/005        |
| * | H | US-2004/0167794                                  | 08-2004         | Shostack et al.     | 705/001        |
| * | I | US-2004/0143526                                  | 07-2004         | Monasterio et al.   | 705/035        |
| * | J | US-6,607,267                                     | 08-2003         | Testardi et al.     | 347/100        |
| * | K | US-6,119,933                                     | 09-2000         | Wong et al.         | 235/380        |
|   | L | US-  |                 |                     |                |
|   | M | US-  |                 |                     |                |

**FOREIGN PATENT DOCUMENTS**

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
|   | N |  |                 |         |      |                |
|   | O |  |                 |         |      |                |
|   | P |  |                 |         |      |                |
|   | Q |  |                 |         |      |                |
|   | R |  |                 |         |      |                |
|   | S |  |                 |         |      |                |
|   | T |  |                 |         |      |                |

**NON-PATENT DOCUMENTS**

|   |   |   |
|---|---|---|
| * |   | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|   | U |   |
|   | V |   |
|   | W |   |
|   | X |   |

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